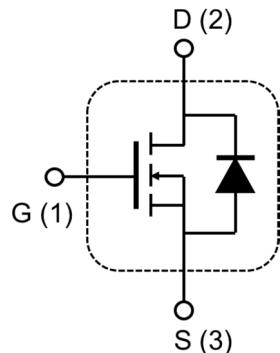


**TSC120F030**

Silicon Carbide Power MOSFET

N-CHANNEL ENHANCEMENT MODE

**TO-247-3L****Inner Circuit****Product Summary**

<b>V<sub>DS</sub></b>	<b>1200V</b>
<b>I<sub>D(@25°C)</sub></b>	<b>80A</b>
<b>R<sub>DS(on)</sub></b>	<b>30mΩ</b>

**Features**

- Low On-Resistance
- Low Capacitance
- Avalanche Ruggedness
- Halogen Free, RoHS Compliant

**Applications**

- SMPS / UPS / PFC
- EV Charging station & Motor Drives
- Power Inverters & DC/DC Converters
- Solar/ Wind Renewable Energy

**Benefits**

- Higher System Efficiency
- Parallel Device Convenience
- High Temperature Application
- High Frequency Operation

**Maximum Ratings (T<sub>c</sub>=25°C)**

Parameter	Symbol	Test Conditions	Value	Unit
Drain – Source Voltage	V <sub>DS, max</sub>	V <sub>GS</sub> =0V, I <sub>D</sub> =100µA	1200	V
Continuous Drain Current	I <sub>D</sub>	V <sub>GS</sub> =20V, T <sub>C</sub> =25°C	80	A
		V <sub>GS</sub> =20V, T <sub>C</sub> =110°C	48	
Pulse Drain Current	I <sub>D, pulse</sub>	t <sub>PW</sub> limitation per Fig.17	200	
Avalanche energy, Single Pulse	E <sub>AS</sub>	V <sub>DD</sub> =100V, I <sub>D</sub> =14A	2.5	J
Power Dissipation	P <sub>D</sub>	T <sub>C</sub> =25°C	338	W
Gate Source Voltage (static)	V <sub>GS, op</sub>	Static	-5/+20	V
Gate Source Voltage (dynamic)	V <sub>GS, max</sub>	AC (f > 1Hz)	-10/+25	
Junction & Storage Temperature	T <sub>j</sub> , T <sub>stg</sub>		-55/+150	°C
Soldering Temperature	T <sub>L</sub>		260	

**Electrical Characteristics ( $T_j=25^\circ\text{C}$ )**

Parameter	Symbol	Test Conditions	Min.	Typ.	Max.	Unit
Drain-Source Breakdown Voltage	$V_{(\text{BR})\text{DSS}}$	$V_{\text{GS}}=0\text{V}, I_{\text{DS}}=100\mu\text{A}$	1200			V
Gate Threshold Voltage	$V_{\text{GS}(\text{th})}$	$V_{\text{DS}}=10\text{V}, I_{\text{DS}}=20\text{mA}$	1.5	2.2	3.5	V
Zero Gate Voltage Drain Current	$I_{\text{DSS}}$	$V_{\text{DS}}=1200\text{V}, V_{\text{GS}}=0\text{V}$		<1	50	$\mu\text{A}$
		$V_{\text{DS}}=1200\text{V}, V_{\text{GS}}=0\text{V}$ $T_j=150^\circ\text{C}$		5	200	
Gate-Source Leakage Current	$I_{\text{GSS}}$	$V_{\text{GS}}=20\text{V}, V_{\text{DS}}=0\text{V}$			250	nA
Drain-Source On-State Resistance	$R_{\text{DS}(\text{on})}$	$V_{\text{GS}}=20\text{V}, I_{\text{DS}}=40\text{A}$		30	40	$\text{m}\Omega$
		$V_{\text{GS}}=20\text{V}, I_{\text{DS}}=40\text{A},$ $T_j=150^\circ\text{C}$		47		
Input Capacitance	$C_{\text{iss}}$	$V_{\text{GS}}=0\text{V}, V_{\text{DS}}=800\text{V}$ $f=1\text{MHz}, V_{\text{AC}}=25\text{mV}$		3917		$\text{pF}$
Output Capacitance	$C_{\text{oss}}$			195		
Reverse Transfer Capacitance	$C_{\text{rss}}$			49		
Effective Output Capacitance, Energy Related	$C_{\text{o(er)}}$	$V_{\text{GS}}=0\text{V},$ $V_{\text{DS}}=0 \text{ to } 800\text{V}$		402		
Effective Output Capacitance, Time Related	$C_{\text{o(tr)}}$	$I_D=\text{const.}, V_{\text{GS}}=0\text{V},$ $V_{\text{DS}}=0 \text{ to } 800\text{V}$		352		
Turn On Delay Time	$t_{\text{d(on)}}$	$V_{\text{DS}}=800\text{V},$ $V_{\text{GS}}=-4/+20\text{V},$ $I_D=40\text{A}, R_L=20\Omega,$ $R_{\text{G(ext)}}=2.7\ \Omega$		31		$\text{ns}$
Rise Time	$t_r$			55		
Turn Off Delay Time	$t_{\text{d(off)}}$			8		
Fall Time	$t_f$			12		
$C_{\text{oss}}$ Stored Energy	$E_{\text{oss}}$	$V_{\text{GS}}=0\text{V}, V_{\text{DS}}=800\text{V}$ $f=1\text{MHz}, V_{\text{AC}}=25\text{mV}$		111		$\mu\text{J}$
Turn-on Switching Energy	$E_{\text{on}}$	$V_{\text{DS}}=800\text{V},$ $V_{\text{GS}}=0/20\text{V}, I_D=40\text{A},$ $R_{\text{G(ext)}}=2.7\ \Omega$		367*		
Turn-off Switching Energy	$E_{\text{off}}$			563*		
Internal Gate Resistance	$R_{\text{G(int.)}}$	$f=1\text{MHz}, V_{\text{AC}}=25\text{mV}$		0.7		$\Omega$

\*Based on the results of calculation, note that the energy loss caused by the reverse recovery of FWD is not included in  $E_{\text{on}}$ .

**Built-in SiC Diode Characteristics ( $T_j=25^\circ\text{C}$ )**

Parameter	Symbol	Test Conditions	Typ.	Unit
Inverse Diode Forward Voltage	$V_{\text{SD}}$	$V_{\text{GS}}=0\text{V}, I_{\text{SD}}=10\text{A}$	3.0	V
Continuous Diode Forward Current	$I_s$	$V_{\text{GS}}=0\text{V}, T_c=25^\circ\text{C}$	56	A
Reverse Recovery Time	$t_{\text{rr}}$	$V_{\text{GS}}=0\text{V},$ $I_{\text{SD}}=30\text{A}, V_{\text{DS}}=400\text{V},$ $di/dt=300\text{A}/\mu\text{s}$	79	ns
Reverse Recovery Charge	$Q_{\text{rr}}$		284	nC
Peak Reverse Recovery Current	$I_{\text{rrm}}$		6.8	A

## Gate Charge Characteristics ( $T_j=25^\circ\text{C}$ )

Parameter	Symbol	Test Conditions	Value	Unit
Gate to Source Charge	$Q_{GS}$	$V_{DS}=800\text{V}$ , $V_{GS}=-5/+20\text{V}$ , $I_D=40\text{A}$	91	$\text{nC}$
Gate to Drain Charge	$Q_{GD}$		88	
Total Gate Charge	$Q_G$		305	
Gate plateau voltage	$V_{pl}$		7.9	$\text{V}$

## Thermal Resistance

Parameter	Symbol	Value	Unit
Thermal Resistance, Junction to Case	$R_{\theta,JC}$	0.37	$\text{K/W}$

## Typical Device Performance

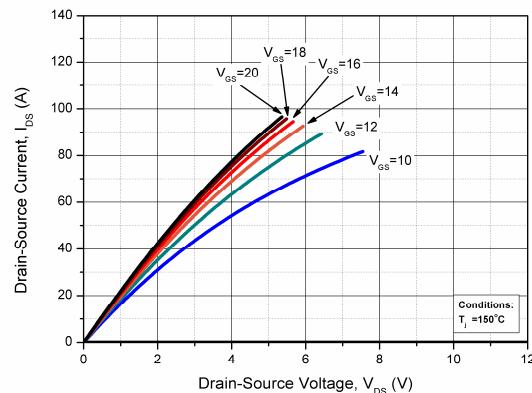
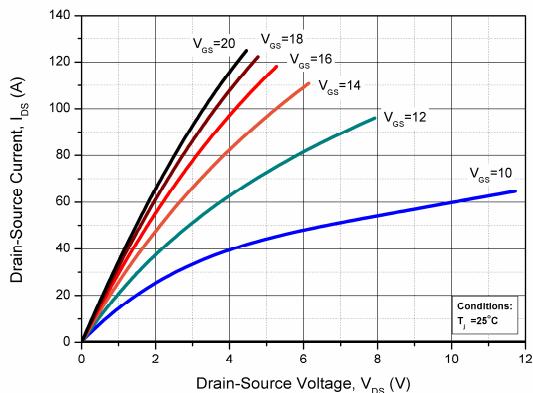


Fig. 1 Forward Output Characteristics at  $T_j = 25^\circ\text{C}$

Fig. 2 Forward Output Characteristics at  $T_j = 150^\circ\text{C}$

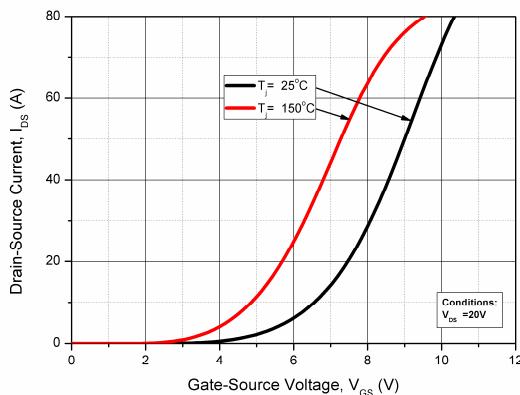
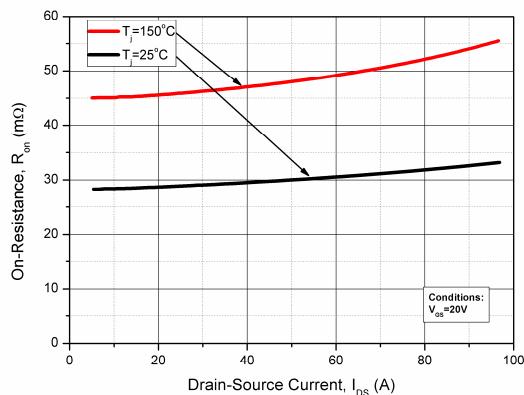
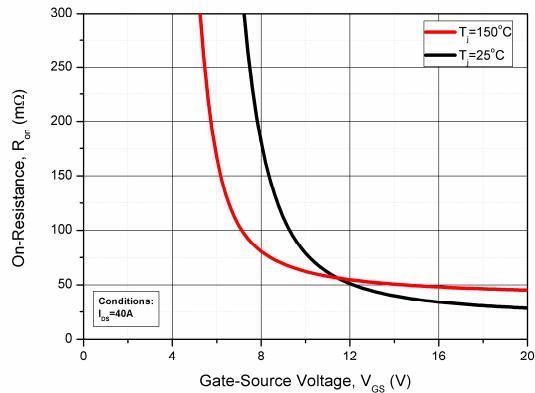


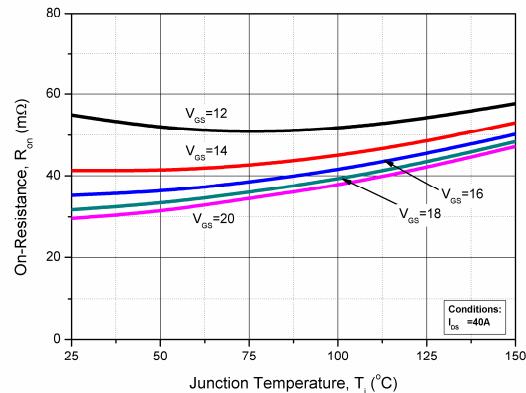
Fig. 3 On-Resistance vs. Drain Current for Various  $T_j$

Fig. 4 Transfer Characteristics for Various  $T_j$

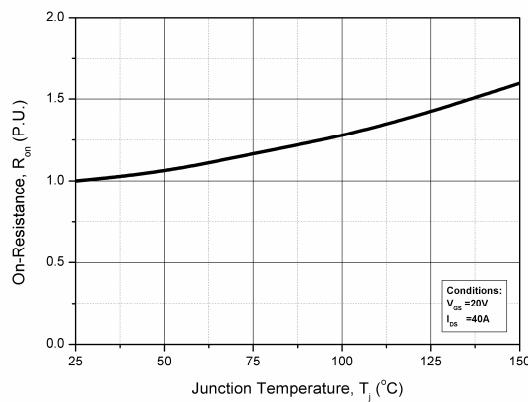
## Typical Device Performance



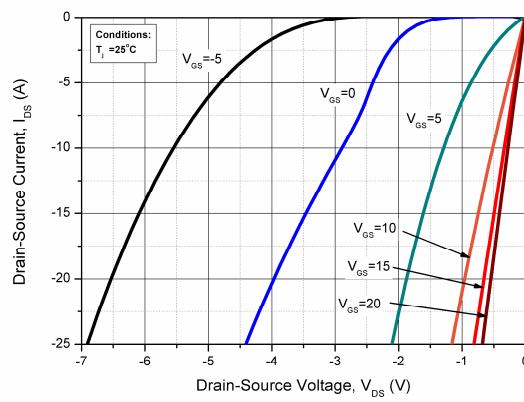
**Fig. 5 On-Resistance vs. Gate Voltage for Various  $T_j$**



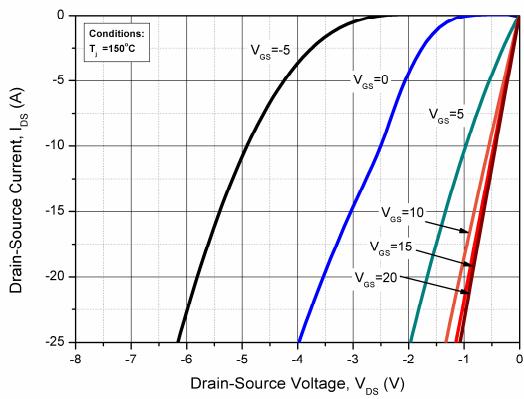
**Fig. 6 On-Resistance vs. Temperature for Various Gate Voltage**



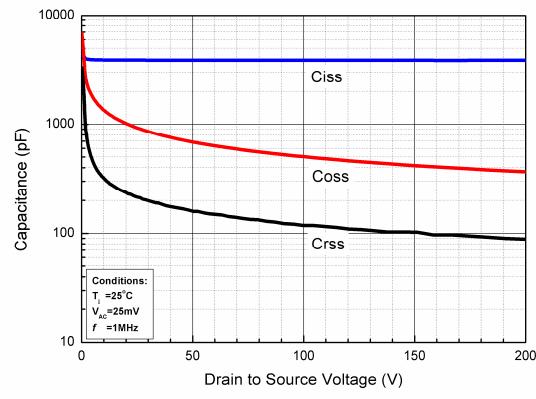
**Fig. 7 Normalized On-Resistance vs. Temperature**



**Fig. 8 Reverse Output Characteristics at  $T_j = 25^\circ\text{C}$**

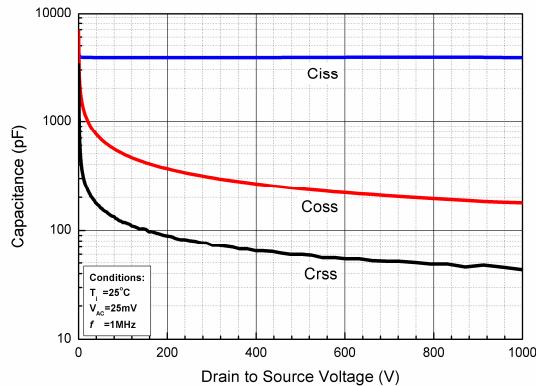


**Fig. 9 Reverse Output Characteristics at  $T_j = 150^\circ\text{C}$**

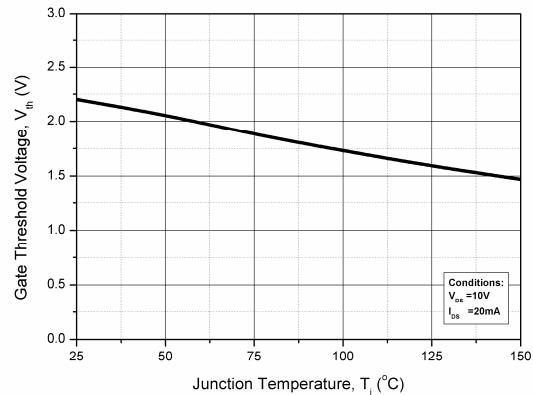


**Fig. 10 Capacitances vs. Drain to Source Voltage (0 - 200V)**

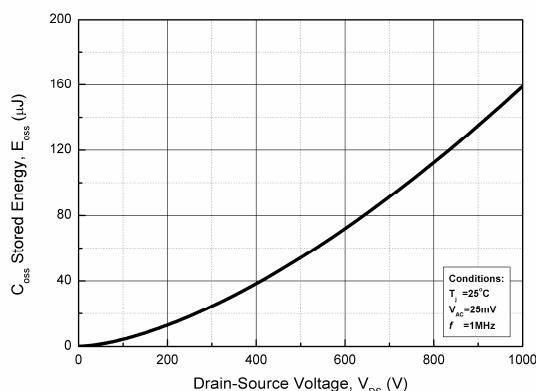
## Typical Device Performance



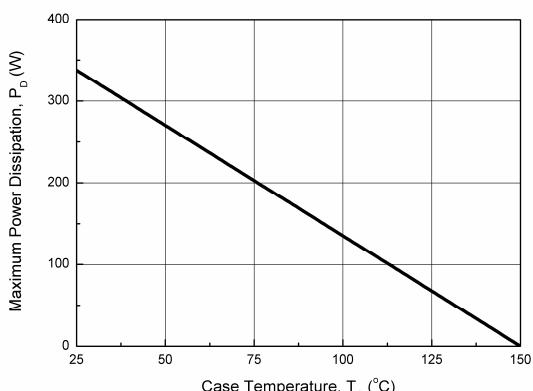
**Fig. 11 Capacitances vs. Drain to Source Voltage (0 - 1000V)**



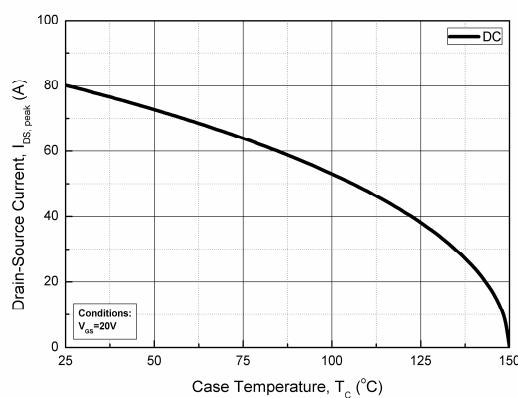
**Fig. 12 Threshold Voltage vs. Temperature**



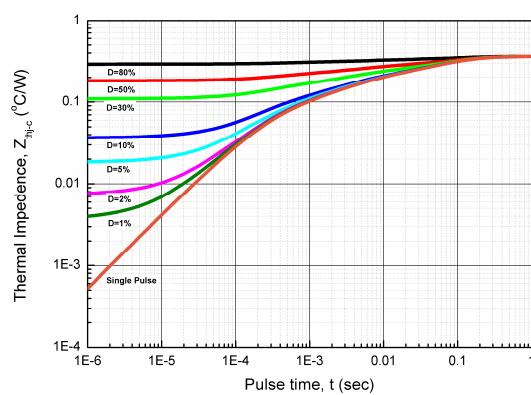
**Fig. 13 Output Capacitor Stored Energy**



**Fig. 14 Maximum Power Dissipation Derating vs. Case Temperature**

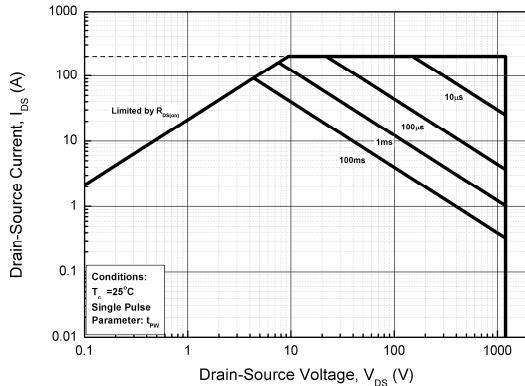


**Fig. 15 Drain Current Derating vs. Case Temperature**

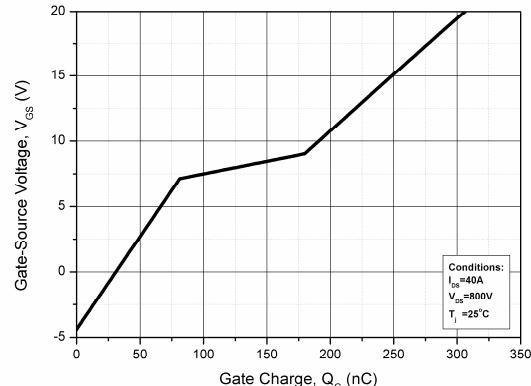


**Fig. 16 Transient Junction to Case Thermal Impedance**

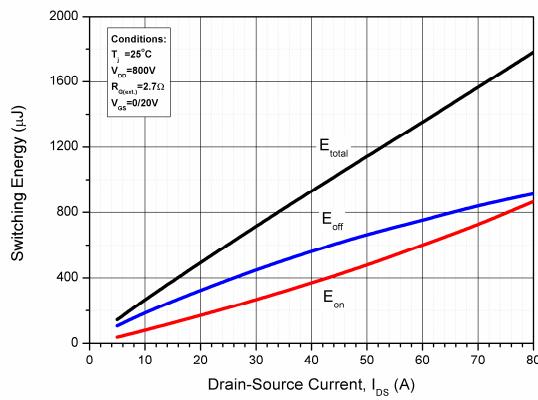
## Typical Device Performance



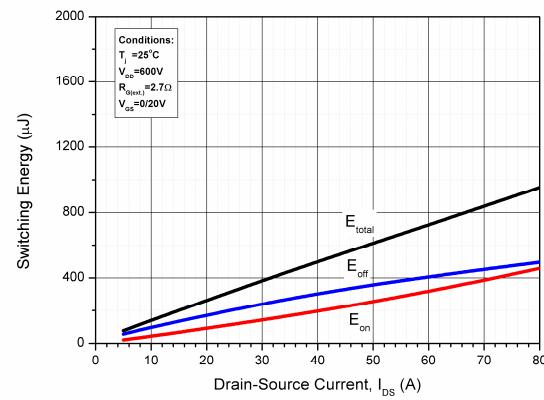
**Fig. 17 Safe Operating Area**



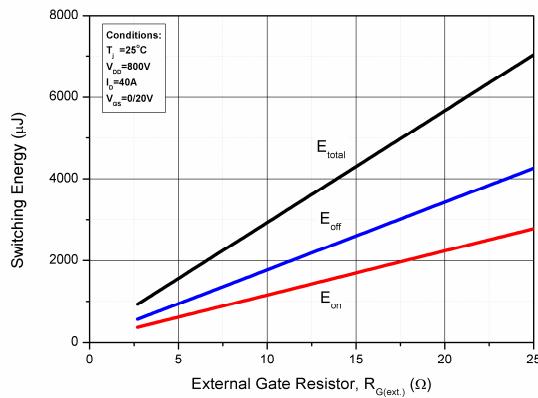
**Fig. 18 Gate Charge Characteristics**



**Fig. 19 Clamped Inductive Switching Energy vs. Drain Current ( $V_{DD}=800\text{V}$ )\***



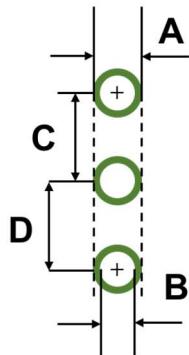
**Fig. 20 Clamped Inductive Switching Energy vs. Drain Current ( $V_{DD}=600\text{V}$ )\***



**Fig. 21 Clamped Inductive Switching Energy vs. External Gate Resistor ( $R_{G(ext)}$ )\***

\*Based on the results of calculation, note that the energy loss caused by the reverse recovery of FWD is not included in  $E_{on}$ .

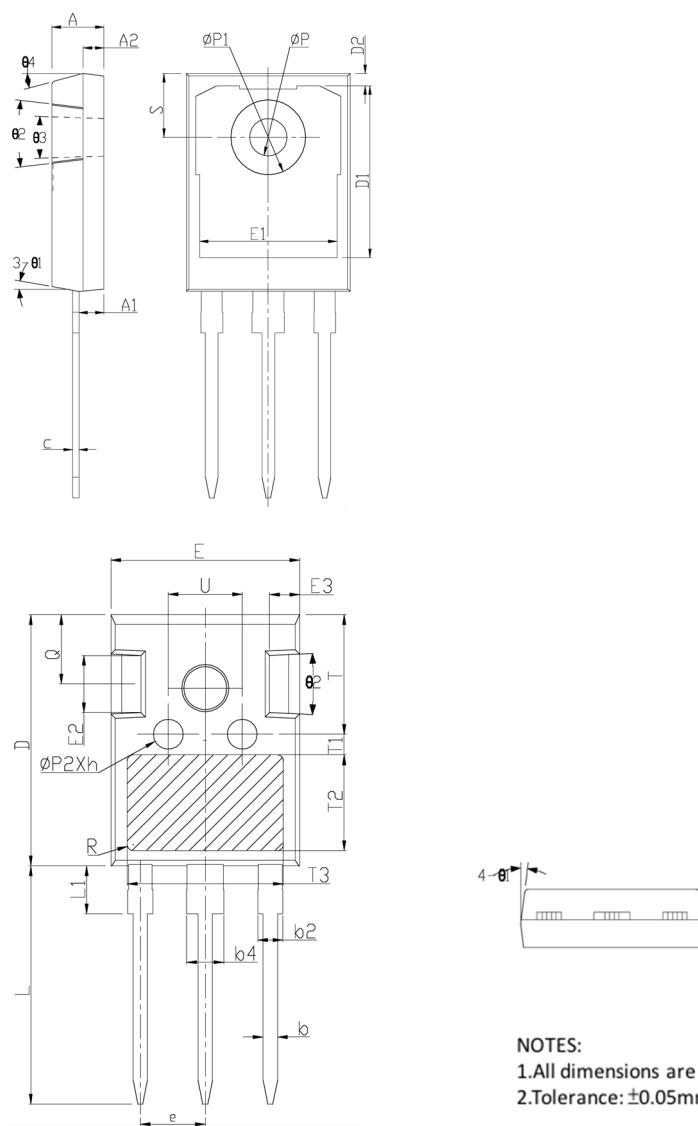
## Recommended Solder Pad Layout (TO-247-3L)



### Mechanical Parameters

Parameter	Symbol	Typical	Unit
Length	A	3.048	mm
	B	2.032	
	C	5.436	
	D	5.436	

## Mechanical Parameters



SYMBOL	DIMENSIONS IN MILLIMETERS		
	MIN	NOM	MAX
A	4.75	5.00	5.25
A1	2.16	2.41	2.66
A2	1.85	2.00	2.15
b	1.11	1.21	1.35
b2	1.90	2.01	2.25
b4	2.90	3.01	3.25
c	0.51	0.61	0.75
D	20.60	21.00	21.40
D1	16.15	16.55	16.95
D2	1.00	1.20	1.40
E	15.50	15.80	16.10
E1	13.00	13.30	13.60
E2	4.70	5.00	5.30
E3	2.25	2.50	2.75
e	5.44BSC		
h	0.00	0.10	0.25
L	19.52	19.92	20.32
L1	-	-	4.30
phi_P	3.35	3.60	3.85
phi_P1	-	-	7.30
phi_P2	2.25	2.50	2.75
Q	5.50	5.80	6.10
S	6.15BSC		
R	0.50REF		
T	9.70	-	10.30
T1	1.65REF		
T2	8.00REF		
T3	12.80REF		
U	5.90	-	6.50
theta_1	4°	7°	10°
theta_2	2°	5°	8°
theta_3	1°	-	2°
theta_4	10°	15°	20°

\*The information provided herein is subject to change without notice.